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SHEET SERIAL NO. 10/800,965 ATTY DOCKET NO. U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE Form PTO 1449 (Modified) 249651US2SDIV **New Divisional Application** APPLICANT LIST OF REFERENCES CITED BY APPLICANT ' Yasufumi TSUMAGARI, et al. FILING DATE **GROUP** Unassigned 2616 Herewith **U.S. PATENT DOCUMENTS EXAMINER** DOCUMENT SUB **FILING DATE** DATE NAME CLASS INITIAL NUMBER CLASS IF APPROPRIATE VES AA 6,253,026 B1 26Jun01 Saeki et al. VEI AB 6,263,155 B1 17Jul01 Saeki et al. M. AC 6,188,835 B1 13Feb01 Grandbois M AD 5,838,301 17Nov98 Okamoto et al. ΑE 6,078,727 20Jun00 Saeki et al. AF 6.360,057 B1 19Mar02 Tsumagari et al. AG 6,181,870 Jan 2001 Okada et al. AH 6,108,486 Aug 2000 Sawabe et al. ΑI 6,088,507 Jul 2000 Yamauchi et al. לענו M AJ 5,784,528 Jul 1998 Yamane et al. MB ΑK 5,771,334 Jun 1998 Yamauchi et al. AL AM AN **FOREIGN PATENT DOCUMENTS** DOCUMENT **TRANSLATION** DATE COUNTRY NUMBER YES NO WB JP 9-245413 AO 19Sep97 JAPAN x JAPAN (with English Abstract) AP JP 11-96730 9Apr99 (corresponding to U.S. Patent Nos. 6,253,026 B1 х 123 and 6,263,155 B1 (listed above) WB AQ JP 6-103317 15Apr94 **JAPAN** AR AS AT ΑU ΑV OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.) Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 1999-131475 (with AW English translation) VERS Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-284024 (with English translation) MRB Explanation of Circumstances concerning Accelerated Examination for Japanese Patent Application No. 2001-284023 (with English translation) ΑZ Additional References sheet(s) attached Examiner **Date Considered** \*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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